

Notice of References Cited	Application/Control No. 10/008,699	Applicant(s)/Patent Under Reexamination NGUYEN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,711,691 B1	03-2004	Howard et al.	713/300
	B	US-6,311,263 B1	10-2001	Barlow et al.	712/36
	C	US-6,536,024	03-2003	Hathaway, David J.	716/6
	D	US-6,330,644	12-2001	Yamashita et al.	711/147
	E	US-6,189,076	02-2001	Fadavi-Ardekani et al.	711/147
	F	US-6,487,647	11-2002	Samson, Eric C.	711/167
	G	US-5,537,582	07-1996	Draeger, Jeffrey S.	713/401
	H	US-5,365,183	11-1994	Mitsuhira, Yuko	327/144
	I	US-5,557,783	09-1996	Oktay et al.	713/401
	J	US-5,339,429	08-1994	Tanaka et al.	712/205
	K	US-6,625,559	09-2003	Helder, Edward R.	702/117
	L	US-6,340,905	01-2002	Schultz, Richard T.	327/161
	M	US-6,597,226	07-2003	Eade et al.	327/292

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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